

UNISONIC TECHNOLOGIES CO., LTD

F2N60-LC1

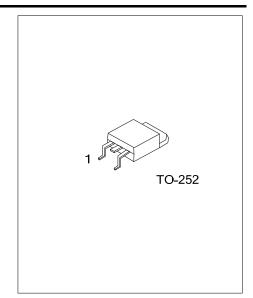
Preliminary

Power MOSFET

2.0A, 600V N-CHANNEL POWER MOSFET

■ DESCRIPTION

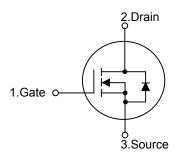
The UTC **F2N60-LC1** is a N-Channel enhancement mode silicon gate power MOSFET with Fast Body Diode, is designed high voltage, high speed power switching applications such, is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient AC to DC converters and bridge circuits.



■ FEATURES

- * $R_{DS(ON)} \le 5.5 \Omega$ @ $V_{GS}=10V$, $I_{D}=1.0A$
- * Fast body diode MOSFET technology
- * High Switching Speed
- * 100% Avalanche Tested

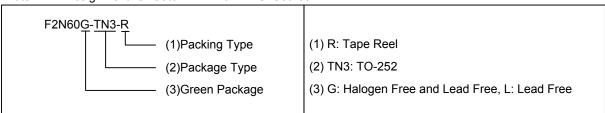
■ SYMBOL



ORDERING INFORMATION

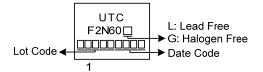
Ordering Number		Dardina	Pin Assignment			Deaking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
F2N60L-TN3-R	F2N60G-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



www.unisonic.com.tw 1 of 6

■ MARKING



■ ABSOLUTE MAXIMUM RATINGS (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	600	V
Gate-Source Voltage		V_{GSS}	±30	V
Drain Current	Continuous	I _D 2		Α
	Pulsed (Note 2)	I_{DM}	4	Α
Avalanche Energy	Energy Single Pulsed (Note 3)		49	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	6	V/ns
Power Dissipation		P_{D}	45	W
Junction Temperature		T_J	+150	°C
Storage Temperature		T_{STG}	-55 ~ + 150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 30mH, I_{AS} = 1.8A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}$ C
- 4. $I_{SD} \le 2.0A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL CHARACTERISTICS

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	100	°C/W	
Junction to Case	θ _{JC}	2.77 (Note)	°C/W	

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

■ ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

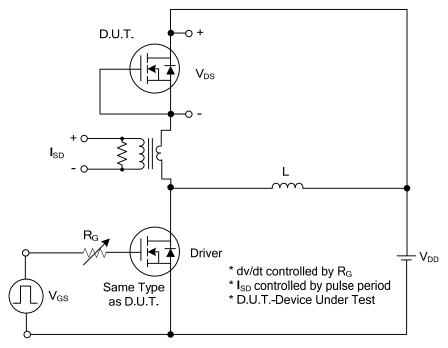
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage		BV _{DSS}	$I_D=250\mu A, V_{GS}=0V$	600			V	
Drain-Source Leakage Current		I _{DSS}	V _{DS} =600V, V _{GS} =0V			10	μΑ	
Gate- Source Leakage Current	Forward		V _{GS} =+30V, V _{DS} =0V			+100	nA	
	Reverse	I_{GSS}	V_{GS} =-30V, V_{DS} =0V			-100	nA	
ON CHARACTERISTICS								
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$			4.0	V	
Static Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} =10V, I _D =1.0A			5.5	Ω	
DYNAMIC PARAMETERS								
Input Capacitance		C_{ISS}			265		pF	
Output Capacitance		Coss	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		31		pF	
Reverse Transfer Capacitance	C_{RSS}			3		pF		
SWITCHING PARAMETERS								
Total Gate Charge (Note 1)		Q_G	\\ -480\\ \\ -10\\ -24		7.5		nC	
Gate to Source Charge		Q_GS	V_{DS} =480V, V_{GS} =10V, I_{D} =2A I_{G} =1mA (Note 1, 2)		2.6		nC	
Gate to Drain Charge		Q_GD	IG-IIIA (Note 1, 2)		1		nC	
Turn-ON Delay Time (Note 1)		$t_{D(ON)}$			5		ns	
Rise Time		t_R	V _{DD} =100V, V _{GS} =10V,		16		ns	
Turn-OFF Delay Time		t _{D(OFF)}	I_D =2A, R_G =25 Ω (Note 1, 2)		24		ns	
Fall-Time		t_{F}			24		ns	
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS								
Maximum Body-Diode Continuous Current		I_S				2	Α	
Maximum Body-Diode Pulsed Current (Note 1)		I _{SM}				4	Α	
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	I _S =2A, V _{GS} =0V			1.4	V	
Body Diode Reverse Recovery Time		t _{rr}	I _S =2A, V _{GS} =0V,		87		ns	
Body Diode Reverse Recovery Charge		Q _{rr}	dI _F /dt=100A/μs		0.3		μC	

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%.

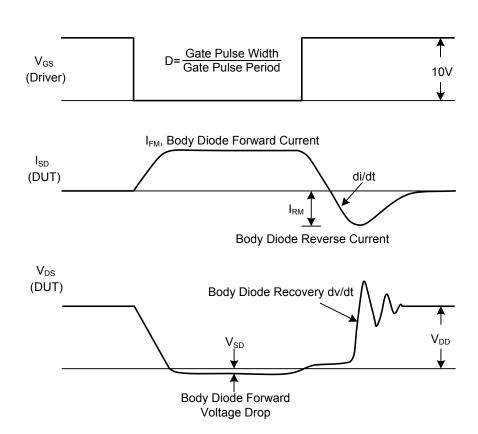
2. Essentially independent of operating temperature.



TEST CIRCUITS AND WAVEFORMS

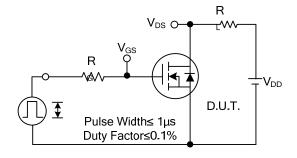


Peak Diode Recovery dv/dt Test Circuit

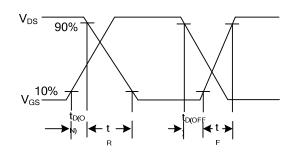


Peak Diode Recovery dv/dt Waveforms

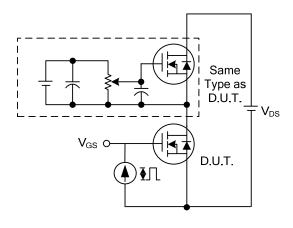
■ TEST CIRCUITS AND WAVEFORMS



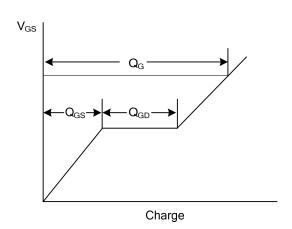
Switching Test Circuit



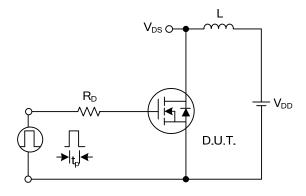
Switching Waveforms



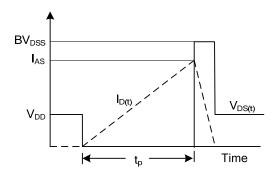
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

UTC assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all UTC products described or contained herein. UTC products are not designed for use in life support appliances, devices or systems where malfunction of these products can be reasonably expected to result in personal injury. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner. UTC reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

